

**Notice of References Cited**

Application/Control No.

10/053,769

Applicant(s)/Patent Under  
Reexamination  
ONO ET AL.

Examiner

Christopher M. Keehan

Art Unit

1712

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,503,961 B1	01-2003	Okazaki et al.	522/173
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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